



AN 370

SIMS Detection Limits of Selected Elements
in GaN Under Normal Depth Profiling Conditions

May 7, 2007 (Version 4.0)

| O ₂ /SIMS Positive Secondary Ion Detection | | Cs/SIMS Negative Secondary Ion Detection | | Cs/SIMS Positive Secondary Ion Detection (CsM ⁺) | |
|--|--------------------------------|---|--------------------------------|--|--------------------------------|
| Element | DL (atoms/cm ³) | Element | DL (atoms/cm ³) | Element | DL (atoms/cm ³) |
| Be | 1E+14 | H* | 8E+16 - 2E+17 | Mg | 5E+15 |
| Li | 1E+14 | C* | 5E+15 - 2E+16 | Zn | 1E+16 |
| B | 1E+15 | O* | 1E+16 - 3E+16 | | |
| Na | 5E+14 | Si | 3E+15 | | |
| Mg | 5E+14 | As | 5E+15 | | |
| Al | 1E+15 | | | | |

*Varies with vacuum conditions

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